

**GL Silicon N-Channel Power MOSFET****General Description**

The GL6009AS-8 uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications. The package form is SOP-8, which accords with the RoHS standard.

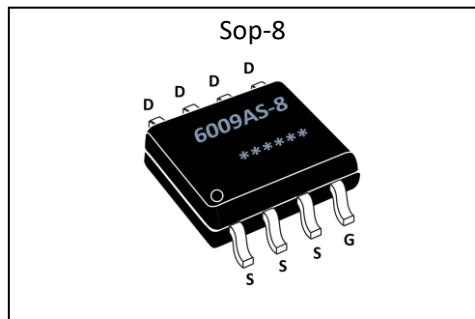
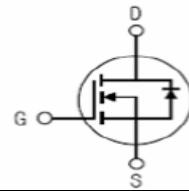
**Features**

- Fast Switching
- Low Gate Charge and Rdson
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test

**Applications**

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

V <sub>DSS</sub>	60	V
I <sub>D</sub>	9	A
P <sub>D</sub>	2.6	W
R <sub>DSON</sub> TYPE	11	mΩ

**Inner Equivalent Principium Chart****Absolute (T<sub>c</sub> = 25°C unless otherwise specified)**

Symbol	Parameter	Rating	Units
V <sub>DSS</sub>	Drain-to-Source Voltage	60	V
I <sub>D</sub>	Continuous Drain Current	9	A
	Continuous Drain Current T <sub>c</sub> = 100 °C	6.5	A
I <sub>DM</sub>	Pulsed Drain Current	36	A
V <sub>GS</sub>	Gate-to-Source Voltage	±20	V
E <sub>AS</sub> a2	Single Pulse Avalanche Energy	50	mJ
E <sub>AR</sub> a1	Avalanche Energy ,Repetitive	11	mJ
I <sub>AR</sub> a1	Avalanche Current	5	A
dv/dt a3	Peak Diode Recovery dv/dt	5.0	V/ns
P <sub>D</sub>	Power Dissipation	2.6	W
T <sub>J</sub> , T <sub>stg</sub>	Operating Junction and Storage Temperature Range	175, -55 to 175	°C
T <sub>L</sub>	Maximum Temperature for Soldering	300	°C



## GL Silicon N-Channel Power MOSFET

## Electrical Characteristics (Tc= 25°C unless otherwise specified)

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V <sub>DSS</sub>	Drain to Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	60	--	--	V
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Bvdss Temperature Coefficient	I <sub>D</sub> =250uA, Reference 25°C	--	0.1	--	V/°C
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>DS</sub> = 60V, V <sub>GS</sub> =0V, T <sub>a</sub> =25°C	--	--	1	μA
		V <sub>DS</sub> =48V, V <sub>GS</sub> =0V, T <sub>a</sub> =125°C	--	--	250	
I <sub>GSS(F)</sub>	Gate to Source Forward Leakage	V <sub>GS</sub> =+20V	--	--	1	μA
I <sub>GSS(R)</sub>	Gate to Source Reverse Leakage	V <sub>GS</sub> =-20V	--	--	-1	μA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R <sub>DS(ON)</sub>	Drain-to-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =9A	--	11	14	mΩ
V <sub>GS(TH)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =250μA	1.0	1.7	2.5	V
Pulse width tp≤380μs, δ≤2%						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =9A	25	--	--	S
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =30V	--	2200	--	pF
C <sub>oss</sub>	Output Capacitance	f=1.0MHz	--	270	--	
C <sub>rss</sub>	Reverse Transfer Capacitance		--	240	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t <sub>d(ON)</sub>	Turn-on Delay Time		--	8.8	--	ns
t <sub>r</sub>	Rise Time	I <sub>D</sub> = 9A, V <sub>DD</sub> =30V	--	7.1	--	
t <sub>d(OFF)</sub>	Turn-Off Delay Time	V <sub>GS</sub> =10V, R <sub>G</sub> =3.0Ω	--	33	--	
t <sub>f</sub>	Fall Time		--	6.0	--	
Q <sub>g</sub>	Total Gate Charge	I <sub>D</sub> =9A, V <sub>DD</sub> =30V	--	61	--	nC
Q <sub>gs</sub>	Gate to Source Charge	V <sub>GS</sub> =10V	--	8.5	--	
Q <sub>gd</sub>	Gate to Drain ( "Miller" )Charge		--	17.6	--	

***GL Silicon N-Channel Power MOSFET***
**Source-Drain Diode Characteristics**

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$I_S$	Continuous Source Current (Body Diode)		--	--	9	A
$I_{SM}$	Maximum Pulsed Current (Body Diode)		--	--	36	A
$V_{SD}$	Diode Forward Voltage	$I_S=9A, V_{GS}=0V$	--	--	1.5	V
$t_{rr}$	Reverse Recovery Time	$I_S=9A, T_j = 25^\circ C$	--	30	--	ns
$Q_{rr}$	Reverse Recovery Charge	$dI_F/dt=100A/\mu s, V_{GS}=0V$	--	45	--	nC

 Pulse width  $t_p \leq 380\mu s, \delta \leq 2\%$ 

Symbol	Parameter	Typ.	Units
$R_{θJA}$	Junction-to-Ambient	48	°C/W

<sup>a1</sup>: Repetitive rating; pulse width limited by maximum junction temperature

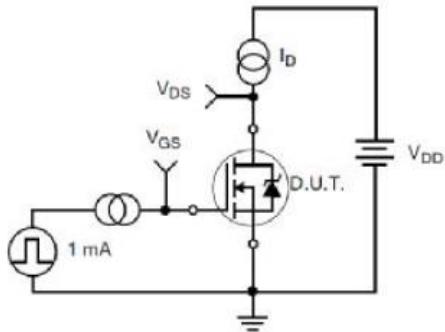
<sup>a2</sup>: EAS condition :  $T_j=25^\circ C, V_{DD}=30V, V_G=10V, L=0.5mH, R_g=25\Omega$ 
<sup>a3</sup>:  $I_{SD}=9A, dI/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}, \text{Start } T_j=25^\circ C$ 
**Test Circuit and Waveform**


Figure 17. Gate Charge Test Circuit

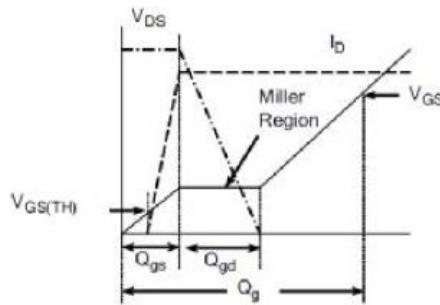


Figure 18. Gate Charge Waveform

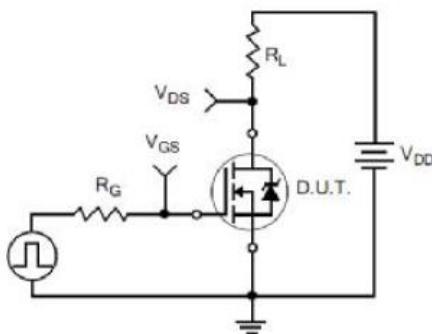


Figure 19. Resistive Switching Test Circuit

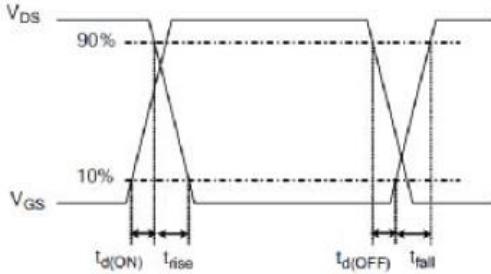
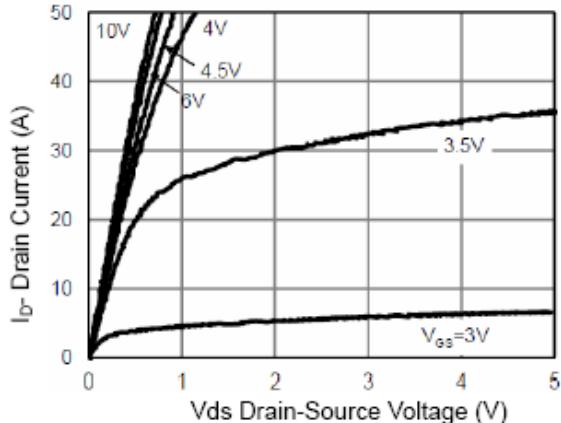
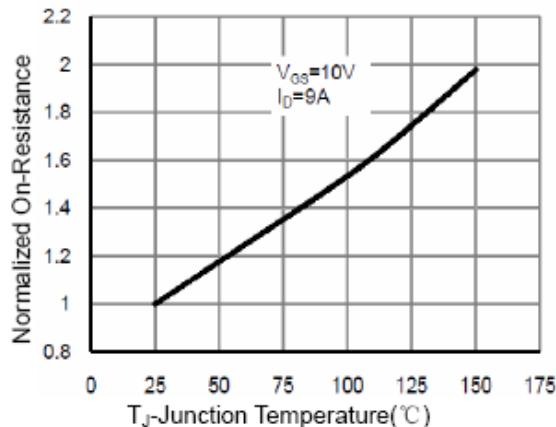
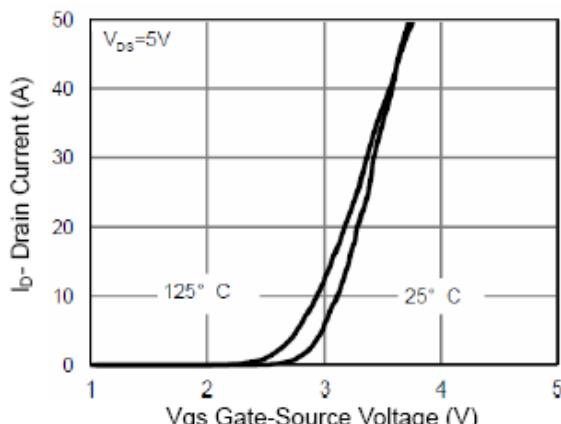
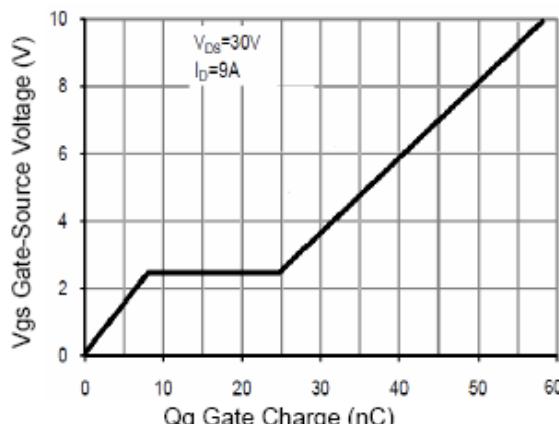
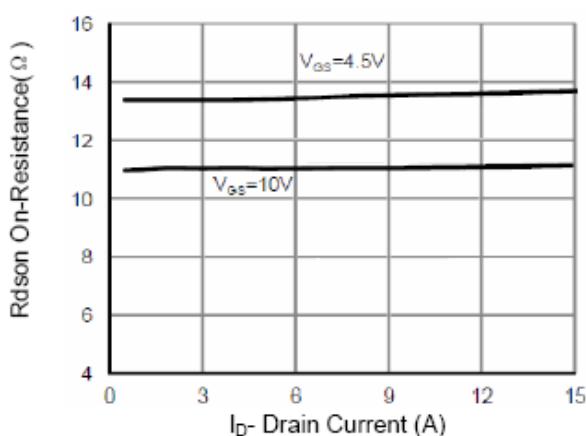
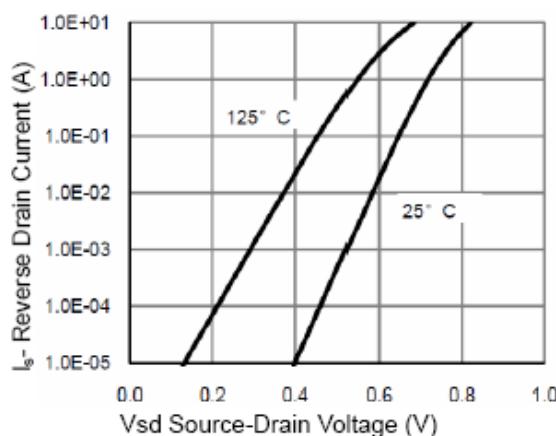
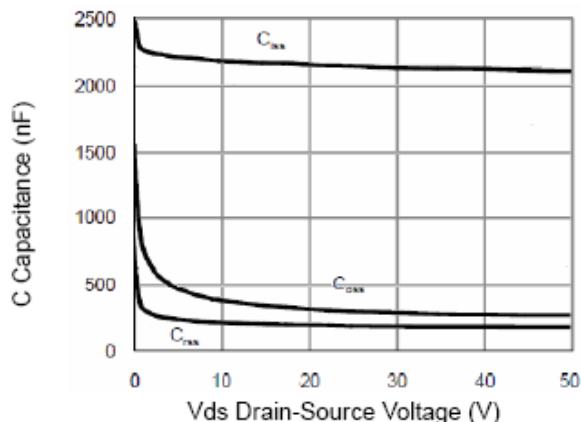
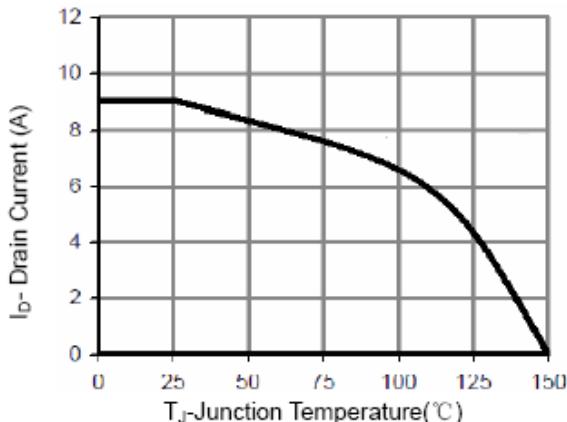
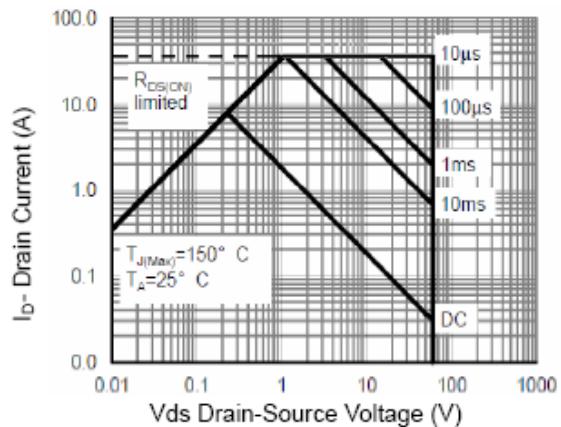
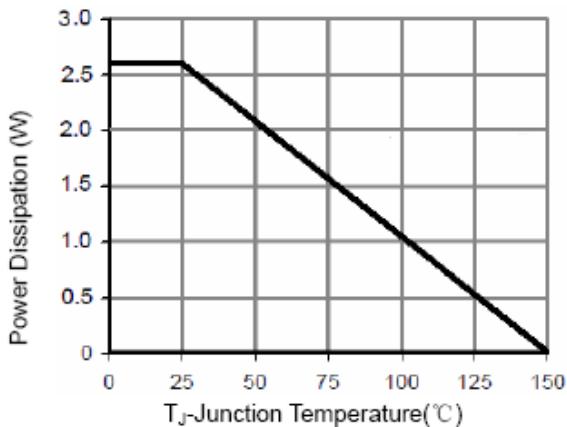
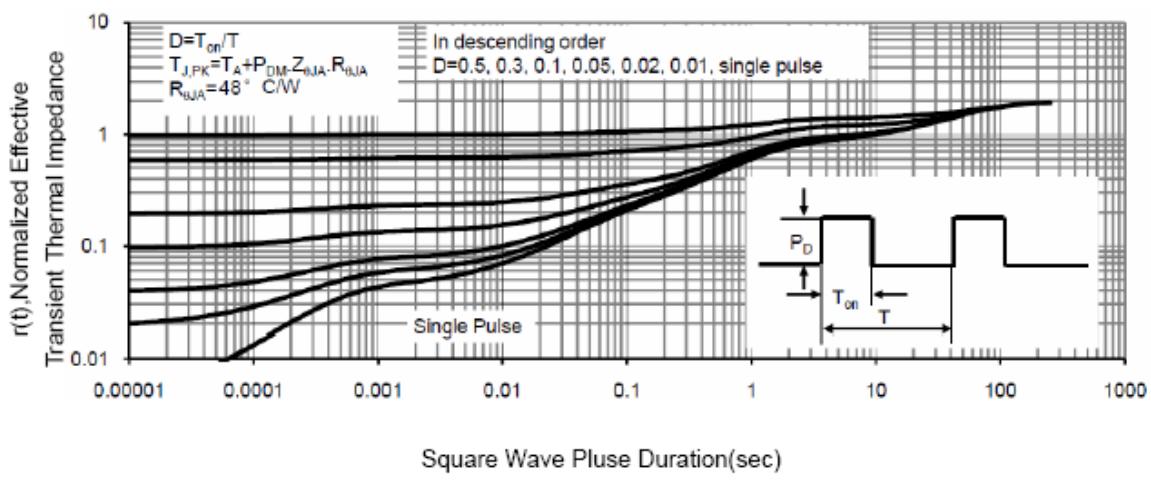


Figure 20. Resistive Switching Waveforms

**GL Silicon N-Channel Power MOSFET**
**Typical Electrical and Thermal Characteristics (Curves)**

**Figure 1 Output Characteristics**

**Figure 4  $R_{DS(on)}$ -JunctionTemperature**

**Figure 2 Transfer Characteristics**

**Figure 5 Gate Charge**

**Figure 3  $R_{DS(on)}$ - Drain Current**

**Figure 6 Source-Drain Diode Forward**

**GL Silicon N-Channel Power MOSFET**

**Figure 7 Capacitance vs Vds**

**Figure 9 Current De-rating**

**Figure 8 Safe Operation Area**

**Figure 10 Power De-rating**

**Figure 11 Normalized Maximum Transient Thermal Impedance**

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